# **BUK7905-40ATE**

# N-channel TrenchPLUS standard level FET

Rev. 02 — 10 February 2009

**Product data sheet** 

## 1. Product profile

### 1.1 General description

Standard level N-channel enhancement mode Field-Effect Transistor (FET) in a plastic package using TrenchMOS technology. The devices include TrenchPLUS diodes for temperature sensing and ElectroStatic Discharge (ESD) protection. This product has been designed and qualified to the appropriate AEC standard for use in automotive critical applications.

### 1.2 Features and benefits

- Allows responsive temperature monitoring due to integrated temperature sensor
- Electrostatically robust due to integrated protection diodes
- Low conduction losses due to low on-state resistance
- Q101 compliant
- Suitable for standard level gate drive sources

### 1.3 Applications

Electrical Power Assisted Steering (EPAS)

Variable Valve Timing for engines

### 1.4 Quick reference data

Table 1. Quick reference

| Symbol              | Parameter  | Conditions   | Min  | Тур   | Max   | Unit |
|---------------------|--|--|------|-------|-------|------|
| $V_{DS}$            | drain-source voltage                                     | $T_j \ge 25 \text{ °C}; T_j \le 175 \text{ °C}$  | -    | -     | 40    | V    |
| Static cha          | racteristics   |  |      |       |       |      |
| R <sub>DSon</sub>   | drain-source on-state resistance                         | $V_{GS} = 10 \text{ V}; I_D = 50 \text{ A};$<br>$T_j = 25 \text{ °C}; \text{ see } \frac{\text{Figure 7}}{\text{Figure 8}}; \text{ see}$ | -    | 4.5   | 5     | mΩ   |
| S <sub>F(TSD)</sub> | temperature sense<br>diode temperature<br>coefficient    | I <sub>F</sub> = 250 μA; T <sub>j</sub> ≥ -55 °C;<br>T <sub>j</sub> ≤ 175 °C   | -1.4 | -1.54 | -1.68 | mV/K |
| V <sub>F(TSD)</sub> | temperature sense<br>diode forward<br>voltage            | $I_F = 250 \mu A; T_j = 25 \degree C$  | 648  | 658   | 668   | mV   |
| $V_{F(TSD)hys}$     | temperature sense<br>diode forward<br>voltage hysteresis | $I_F \le 250 \ \mu A; T_j = 25 \ ^{\circ}C;$<br>$I_F \ge 125 \ \mu A$  | 25   | 32    | 50    | mV   |
|                     |  |  |      |       |       |      |



# 2. Pinning information

Table 2. Pinning information

| Pin | Symbol | Description                       | Simplified outline               | Graphic symbol |
|-----|--------|-----------------------------------|----------------------------------|----------------|
| 1   | G      | gate                              |                                  |                |
| 2   | Α      | anode                             | mb                               | D A            |
| 3   | D      | drain                             |                                  | G A I A        |
| 4   | K      | cathode                           |                                  | (本 下 平)        |
| 5   | S      | source                            |                                  |                |
| mb  | D      | mounting base; connected to drain | 1 2 3 4 5<br>SOT263B<br>(TO-220) | S K<br>mbl317  |

# 3. Ordering information

Table 3. Ordering information

| Type number   | Package |  |         |
|---------------|---------|--|---------|
|               | Name    | Description  | Version |
| BUK7905-40ATE | TO-220  | plastic single-ended package; heatsink mounted; 1 mounting hole; 5-lead TO-220 | SOT263B |

## 4. Limiting values

Table 4. Limiting values

In accordance with the Absolute Maximum Rating System (IEC 60134).

| Symbol                     | Parameter  | Conditions   |     | Min  | Max  | Unit |
|----------------------------|--|--|-----|------|------|------|
| $V_{DS}$                   | drain-source voltage                               | $T_j \ge 25 \text{ °C}; T_j \le 175 \text{ °C}$  |     | -    | 40   | V    |
| $V_{GS}$                   | gate-source voltage                                |  |     | -20  | 20   | V    |
| I <sub>D</sub>             | drain current                                      | T <sub>mb</sub> = 25 °C; V <sub>GS</sub> = 10 V; see <u>Figure 2</u> ; see <u>Figure 3</u>                 | [1] | -    | 155  | Α    |
|                            |  |  | [2] | -    | 75   | Α    |
|                            |  | T <sub>mb</sub> = 100 °C; V <sub>GS</sub> = 10 V; see <u>Figure 2</u>                                      | [2] | -    | 75   | Α    |
| $I_{DM}$                   | peak drain current                                 | $T_{mb} = 25 \text{ °C}; t_p \le 10 \text{ µs}; \text{ pulsed}; \text{ see } \frac{\text{Figure 3}}{}$     |     | -    | 620  | Α    |
| P <sub>tot</sub>           | total power dissipation                            | T <sub>mb</sub> = 25 °C; see <u>Figure 1</u>   |     | -    | 272  | W    |
| I <sub>GS(CL)</sub>        | gate-source clamping                               | continuous   |     | -    | 10   | mA   |
|                            | current  | pulsed; $t_p = 5 \text{ ms}$ ; $\delta = 0.01$   |     | -    | 50   | mA   |
| V <sub>isol(FET-TSD)</sub> | FET to temperature sense diode isolation voltage   |  |     | -100 | 100  | V    |
| T <sub>stg</sub>           | storage temperature                                |  |     | -55  | 175  | °C   |
| Tj                         | junction temperature                               |  |     | -55  | 175  | °C   |
| Source-drai                | n diode  |  |     |      |      |      |
| I <sub>S</sub>             | source current                                     | $T_{mb} = 25  ^{\circ}C$   | [1] | -    | 155  | Α    |
|                            |  |  | [2] | -    | 75   | Α    |
| I <sub>SM</sub>            | peak source current                                | $t_p \le 10 \ \mu s$ ; pulsed; $T_{mb} = 25 \ ^{\circ}C$   |     | -    | 620  | Α    |
| Avalanche r                | uggedness  |  |     |      |      |      |
| E <sub>DS(AL)S</sub>       | non-repetitive<br>drain-source<br>avalanche energy | $I_D$ = 75 A; $V_{sup}$ ≤ 40 V; $R_{GS}$ = 50 $\Omega$ ; $V_{GS}$ = 10 V; $T_{j(init)}$ = 25 °C; unclamped |     | -    | 1.46 | J    |
| Electrostation             | discharge  |  |     |      |      |      |
| V <sub>esd</sub>           | electrostatic<br>discharge voltage                 | HBM; C = 100 pF; R = 1.5 kΩ  |     | -    | 6    | kV   |

<sup>[1]</sup> Current is limited by power dissipation chip rating.

<sup>[2]</sup> Continuous current is limited by package.

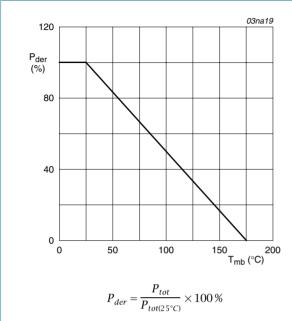


Fig 1. Normalized total power dissipation as a function of mounting base temperature

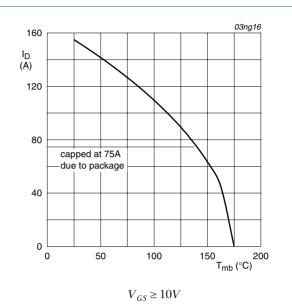
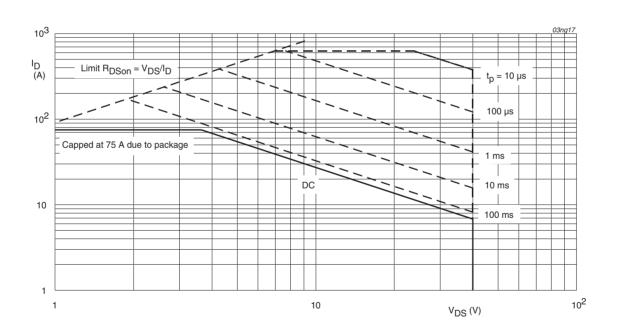


Fig 2. Continuous drain current as a function of mounting base temperature



 $T_{mb} = 25$ °C; $I_{DM}$ is single pulse

Fig 3. Safe operating area; continuous and peak drain currents as a function of drain-source voltage

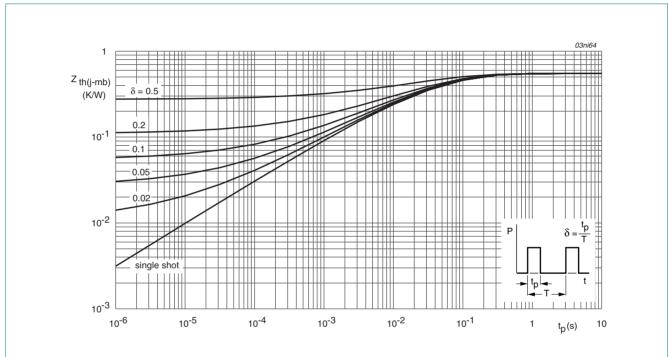
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#### Thermal characteristics 5.

**Thermal characteristics** Table 5.

**Product data sheet** 

| Symbol                | Parameter   | Conditions            | Min | Тур | Max  | Unit |
|-----------------------|---|-----------------------|-----|-----|------|------|
| $R_{th(j-a)}$         | thermal resistance from junction to ambient       | vertical in still air | -   | 60  | -    | K/W  |
| R <sub>th(j-mb)</sub> | thermal resistance from junction to mounting base | see Figure 4          | -   | -   | 0.55 | K/W  |



Transient thermal impedance from junction to mounting base as a function of pulse duration Fig 4.

## 6. Characteristics

Table 6. Characteristics

| Symbol                 | Parameter  | Conditions   | Min  | Тур   | Max   | Unit |
|------------------------|--|--|------|-------|-------|------|
| Static cha             | racteristics   |  |      |       |       |      |
| V <sub>(BR)DSS</sub>   | drain-source   | $I_D = 0.25 \text{ mA}; V_{GS} = 0 \text{ V}; T_j = 25 \text{ °C}$                                     | 40   | -     | -     | V    |
|                        | breakdown voltage  | $I_D = 0.25 \text{ mA}; V_{GS} = 0 \text{ V}; T_j = -55 \text{ °C}$                                    | 36   | -     | -     | V    |
| $V_{GS(th)}$           | gate-source threshold voltage                            | $I_D = 1 \text{ mA}$ ; $V_{DS} = V_{GS}$ ; $T_j = 25 \text{ °C}$ ; see Figure 9                        | 2    | 3     | 4     | V    |
|                        |  | $I_D = 1 \text{ mA}$ ; $V_{DS} = V_{GS}$ ; $T_j = 175 \text{ °C}$ ; see Figure 9                       | 1    | -     | -     | V    |
|                        |  | $I_D = 1 \text{ mA}$ ; $V_{DS} = V_{GS}$ ; $T_j = -55 \text{ °C}$ ; see Figure 9                       | -    | -     | 4.4   | V    |
| I <sub>DSS</sub>       | drain leakage current                                    | $V_{DS} = 40 \text{ V}; V_{GS} = 0 \text{ V}; T_j = 25 \text{ °C}$                                     | -    | 0.1   | 10    | μΑ   |
|                        |  | $V_{DS} = 40 \text{ V}; V_{GS} = 0 \text{ V}; T_j = 175 \text{ °C}$                                    | -    | -     | 250   | μΑ   |
| $V_{(BR)GSS}$          | gate-source breakdown<br>voltage                         | $I_G = 1 \text{ mA}; V_{DS} = 0 \text{ V}; T_j \le 175 \text{ °C};$<br>$T_j \ge -55 \text{ °C}$        | 20   | 22    | -     | V    |
|                        |  | $I_G = -1 \text{ mA}; V_{DS} = 0 \text{ V}; T_j \le 175 \text{ °C};$<br>$T_j \ge -55 \text{ °C}$       | 20   | 22    | -     | V    |
| I <sub>GSS</sub>       | gate leakage current                                     | $V_{DS} = 0 \text{ V}; V_{GS} = 10 \text{ V}; T_j = 25 \text{ °C}$                                     | -    | 22    | 1000  | nΑ   |
|                        |  | $V_{DS} = 0 \text{ V}; V_{GS} = -10 \text{ V}; T_j = 25 \text{ °C}$                                    | -    | 22    | 1000  | nA   |
|                        |  | V <sub>DS</sub> = 0 V; V <sub>GS</sub> = 10 V; T <sub>j</sub> = 175 °C                                 | -    | -     | 10    | μΑ   |
|                        |  | $V_{DS} = 0 \text{ V}; V_{GS} = -10 \text{ V}; T_j = 175 ^{\circ}\text{C}$                             | -    | -     | 10    | μΑ   |
| R <sub>DSon</sub>      | drain-source on-state resistance                         | $V_{GS} = 10 \text{ V}; I_D = 50 \text{ A}; T_j = 25 ^{\circ}\text{C};$<br>see Figure 7; see Figure 8  | -    | 4.5   | 5     | mΩ   |
|                        |  | $V_{GS} = 10 \text{ V}; I_D = 50 \text{ A}; T_j = 175 ^{\circ}\text{C};$<br>see Figure 7; see Figure 8 | -    | -     | 9.5   | mΩ   |
| V <sub>F(TSD)</sub>    | temperature sense diode forward voltage                  | $I_F = 250 \mu A; T_j = 25 \text{ °C}$   | 648  | 658   | 668   | mV   |
| S <sub>F(TSD)</sub>    | temperature sense<br>diode temperature<br>coefficient    | $I_F = 250 \ \mu A; T_j \ge -55 \ ^{\circ}C; T_j \le 175 \ ^{\circ}C$                                  | -1.4 | -1.54 | -1.68 | mV/k |
| V <sub>F(TSD)hys</sub> | temperature sense<br>diode forward voltage<br>hysteresis | $I_F \le 250 \ \mu A; \ I_F \ge 125 \ \mu A; \ T_j = 25 \ ^{\circ}C$                                   | 25   | 32    | 50    | mV   |
| Dynamic o              | haracteristics   |  |      |       |       |      |
| Q <sub>G(tot)</sub>    | total gate charge  | $I_D = 25 \text{ A}; V_{DS} = 32 \text{ V}; V_{GS} = 10 \text{ V};$                                    | -    | 118   | -     | nC   |
| $Q_{GS}$               | gate-source charge                                       | T <sub>j</sub> = 25 °C; see <u>Figure 14</u>   | -    | 16    | -     | nC   |
| $Q_{GD}$               | gate-drain charge  |  | -    | 57    | -     | nC   |
| C <sub>iss</sub>       | input capacitance  | $V_{GS} = 0 \text{ V}; V_{DS} = 25 \text{ V}; f = 1 \text{ MHz};$                                      | -    | 4500  | -     | pF   |
| C <sub>oss</sub>       | output capacitance                                       | T <sub>j</sub> = 25 °C; see <u>Figure 12</u>   | -    | 1500  | -     | pF   |
| C <sub>rss</sub>       | reverse transfer capacitance                             |  | -    | 960   | -     | pF   |

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Table 6. Characteristics ... continued

| Symbol              | Parameter                  | Conditions  | Min | Тур  | Max | Unit |
|---------------------|----------------------------|---|-----|------|-----|------|
| t <sub>d(on)</sub>  | turn-on delay time         | $V_{DS} = 30 \text{ V}; R_L = 1.2 \Omega; V_{GS} = 10 \text{ V};$                     | -   | 35   | -   | ns   |
| t <sub>r</sub>      | rise time                  | $R_{G(ext)} = 10 \Omega; T_j = 25 \text{ °C}$   | -   | 115  | -   | ns   |
| t <sub>d(off)</sub> | turn-off delay time        |   | -   | 155  | -   | ns   |
| t <sub>f</sub>      | fall time                  |   | -   | 110  | -   | ns   |
| L <sub>D</sub>      | internal drain inductance  | from upper edge of mounting base to centre of die; $T_j = 25$ °C                      | -   | 2.5  | -   | nΗ   |
| L <sub>S</sub>      | internal source inductance | from source lead to source bond pad; $T_j = 25  ^{\circ}\text{C}$                     | -   | 7.5  | -   | nΗ   |
| Source-dr           | ain diode                  |   |     |      |     |      |
| $V_{SD}$            | source-drain voltage       | $I_S = 40 \text{ A}$ ; $V_{GS} = 0 \text{ V}$ ; $T_j = 25 \text{ °C}$ ; see Figure 17 | -   | 0.85 | 1.2 | V    |
| t <sub>rr</sub>     | reverse recovery time      | $I_S = 20 \text{ A}; dI_S/dt = -100 \text{ A/}\mu\text{s}; V_{GS} = -10 \text{ V};$   | -   | 96   | -   | ns   |
| Q <sub>r</sub>      | recovered charge           | $V_{DS} = 30 \text{ V}; T_j = 25 \text{ °C}$  | -   | 224  | -   | nC   |

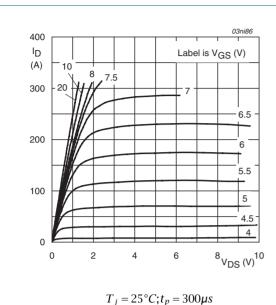
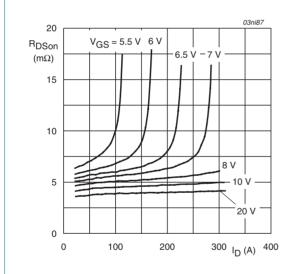
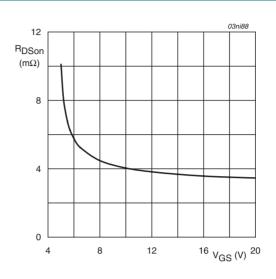


Fig 5. Output characteristics: drain current as a function of drain-source voltage; typical values

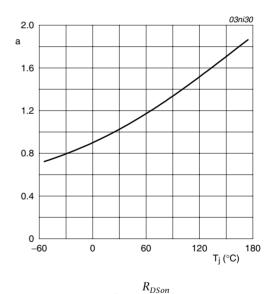


 $T_j=25\,^{\circ}C; t_p=300\mu s$  Fig 7. Drain-source on-state resistance as a function of drain current; typical values



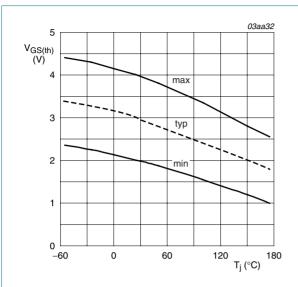
$$T_j = 25^{\circ}C; I_D = 50A$$

Fig 6. Drain-source on-state resistance as a function of gate-source voltage; typical values



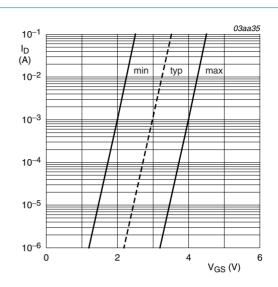
 $a = \frac{1}{R_{DSon(25^{\circ}C)}}$ 

Fig 8. Normalized drain-source on-state resistance factor as a function of junction temperature



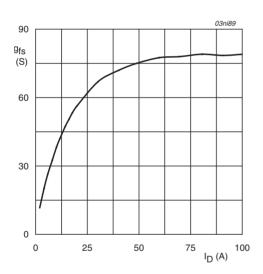
 $I_D = 1 \, mA; V_{DS} = V_{GS}$ 

Fig 9. Gate-source threshold voltage as a function of junction temperature



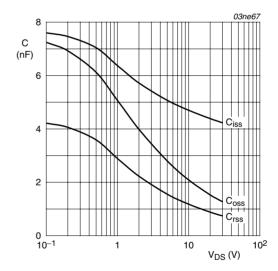
$$T_{j} = 25 \,^{\circ}C; V_{DS} = 5V$$

Fig 10. Sub-threshold drain current as a function of gate-source voltage



 $T_i = 25^{\circ}C; V_{DS} = 25V$ 

Fig 11. Forward transconductance as a function of drain current; typical values



 $V_{GS} = 0V; f = 1MHz$ 

Fig 12. Input, output and reverse transfer capacitances as a function of drain-source voltage; typical values

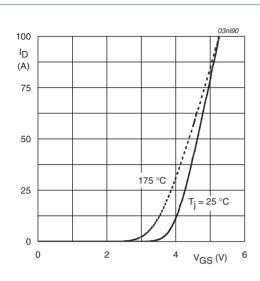


Fig 13. Transfer characteristics: drain current as a function of gate-source voltage; typical values

 $V_{DS} = 25V$ 

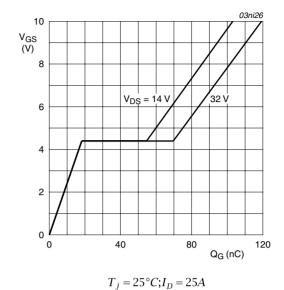


Fig 14. Gate-source voltage as a function of turn-on gate charge; typical values

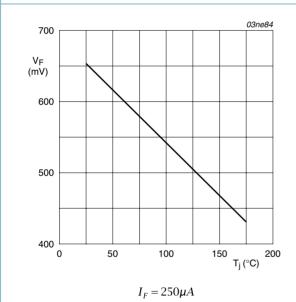
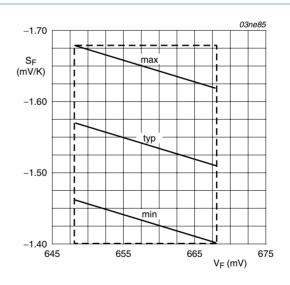
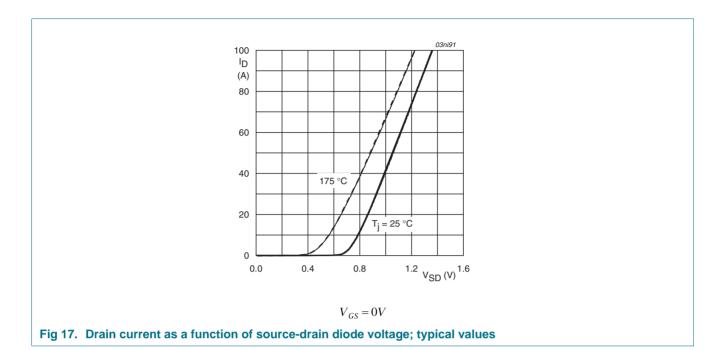


Fig 15. Forward voltage of temperature sense diode as a function of junction temperature; typical values



 $V_F$  at  $T_i = 25^{\circ}C$ ;  $I_F = 250 \mu A$ 

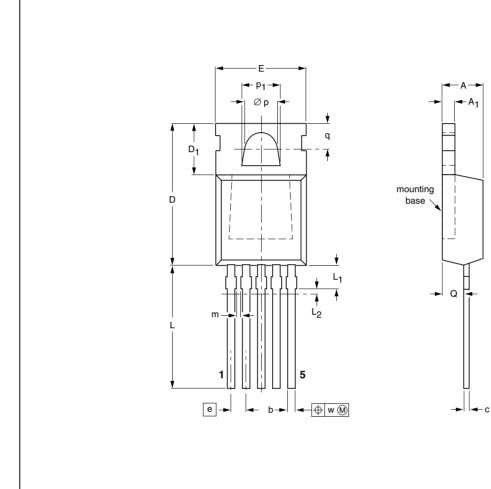
Fig 16. Temperature coefficient of temperature sense diode as a function of forward voltage; typical values



## 7. Package outline

Plastic single-ended package; heatsink mounted; 1 mounting hole; 5-lead TO-220

SOT263B



### 0 5 10 mm L....scale

#### **DIMENSIONS (mm are the original dimensions)**

| UNIT | A          | A <sub>1</sub> | b            | С          | D            | D <sub>1</sub> | E           | е   | L            | L <sub>1</sub> <sup>(1)</sup> | L <sub>2</sub> <sup>(2)</sup> | m          | ∅p         | P <sub>1</sub> | q          | Q          | w   |
|------|------------|----------------|--------------|------------|--------------|----------------|-------------|-----|--------------|-------------------------------|-------------------------------|------------|------------|----------------|------------|------------|-----|
| mm   | 4.5<br>4.1 | 1.39<br>1.27   | 0.85<br>0.70 | 0.7<br>0.4 | 15.8<br>15.2 | 6.4<br>5.9     | 10.3<br>9.7 | 1.7 | 15.0<br>13.5 | 2.4<br>1.6                    | 0.5                           | 0.8<br>0.6 | 3.8<br>3.6 | 4.3<br>4.1     | 3.0<br>2.7 | 2.6<br>2.2 | 0.4 |

#### Notes

- 1. Terminal dimensions are uncontrolled in this zone.
- 2. Positional accuracy of the terminals is controlled in this zone.

| OUTLINE |     | REFER         | ENCES | EUROPEAN   | ISSUE DATE |
|---------|-----|---------------|-------|------------|------------|
| VERSION | IEC | JEDEC         | EIAJ  | PROJECTION | ISSUE DATE |
| SOT263B |     | 5-lead TO-220 |       |            | 01-01-11   |

Fig 18. Package outline SOT263B (TO-220)

# 8. Revision history

### Table 7. Revision history

| Document ID   | Release date   | Data sheet status      | Change notice            | Supersedes          |  |  |
|---|--|------------------------|--------------------------|---------------------|--|--|
| BUK7905-40ATE_2   | 20090210   | Product data sheet     | -                        | BUK71_7905_40ATE-01 |  |  |
| Modifications:  • The format of this data sheet has been redesigned to comply with the new identity guidelines of NXP Semiconductors. |  |                        |                          |                     |  |  |
|   | <ul> <li>Legal texts have been adapted to the new company name where appropriate.</li> </ul> |                        |                          |                     |  |  |
|   | <ul> <li>Type numb</li> </ul>  | er BUK7905-40ATE separ | ated from data sheet BUh | (71_7905_40ATE-01.  |  |  |
| BUK71_7905_40ATE-01<br>(9397 750 11694)   | 20030820   | Product data sheet     | -                        | -                   |  |  |

### 9. Legal information

#### 9.1 Data sheet status

| Document status [1][2]         | Product status[3] | Definition  |
|--------------------------------|-------------------|---|
| Objective [short] data sheet   | Development       | This document contains data from the objective specification for product development. |
| Preliminary [short] data sheet | Qualification     | This document contains data from the preliminary specification.                       |
| Product [short] data sheet     | Production        | This document contains the product specification.                                     |

- [1] Please consult the most recently issued document before initiating or completing a design.
- [2] The term 'short data sheet' is explained in section "Definitions"
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# **BUK7905-40ATE**

### N-channel TrenchPLUS standard level FET

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